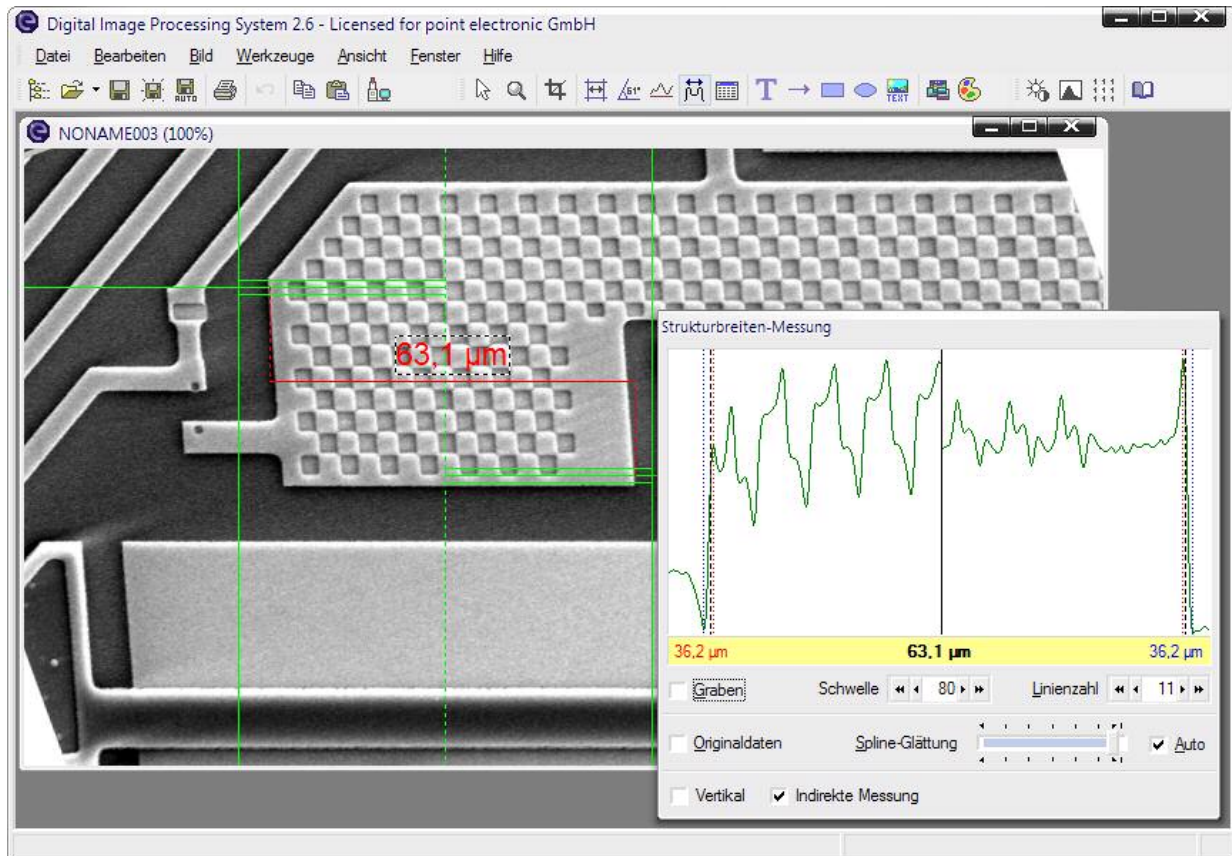




## Semi-automatic structure measurement

An add-on for the Digital Image Processing System DIPS



- semi-automatic measurement of semiconductor structures to minimize measurement errors
- threshold method: the user can select the edges to measure by mouse, the software automatically aligns the measurement cursors to the specified threshold between edge minimum and edge maximum
- several lines can be averaged for the measurement
- spline interpolation for noise suppression, enables measurements in sub-pixel range
- line profile for visual control and display of the measured distance in the image
- measured distance can be burned into the image together with a dimensioning label
- measured values can be taken over into a measurement table